

Search Notes

Application/Control No.

10/780,939

Examiner

James D. Ewart

Applicant(s)/Patent under
Reexamination

LEE, CHANG-KYU

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	9	6/26/2006	JDE
	13.3		
	26.1		
	63.4		
	67.11		
	68		
	82		
	115.1		
	115.4		
	121		
	123		
	129		
	193.1		
	226.1		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
same as	above	6/27/2006	JDE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

(b) (5) DPP, (b) (7)(C), (b) (7)(D)

James D. Ewart

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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
same as	above	6/26/2006	JDE

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